SN54LS299, SN54S299, SN74LS299, SN74S299 8-BIT UNIVERSAL SHIFT/STORAGE REGISTERS

SDLS156

MARCH 1974 - REVISED MARCH 1988

 Multiplexed Inpu Improved Bit De 		de	SN54LS299, SN54S299 J OR W PACKAGE SN74LS299, SN74S299 DW OR N PACKAG (TOP VIEW)	
 Four Modes of C Hold (Store) Shift Right 	perations: Shift Left Load Data			
Operates with O	·	•	$\begin{array}{c} C \land Q_{C} \\ C \land Q_{C} \\ A \land Q_{A} \\ A \land Q_{A} \\ Q_{A} \\ Q_{A} \\ Q_{A} \\ \end{array} \begin{array}{c} 15 \\ 14 \\ 0 \\ 0 \\ 0 \\ 0 \\ 0 \\ 0 \\ 0 \\ 0 \\ 0 \\ $	
 3-State Outputs Can Be Cascade				
 SN54LS323 and 5 Have Synchrono 		milar But	SN54LS299, SN54S299 FK PACKAGE (TOP VIEW)	
	ish-Down Registe a, and Accumula		Віб В З Б G/QG] 4 18 [SL E/OE] 5 17 [QH' C/QC] 6 16 [JH/QH	
т үре 1LS299	GUARANTEED SHIFT (CLOCK) FREQUENCY 25 MHz	TYPICAL POWER DISSIPATION 175 mW	A/ Q_A 7 15 (F/Q_F $Q_{A'}$ 8 14 (D/Q_D 10 10 11 12 13 10 $G = \times \infty$	
5299	50 MHz	700 mW	Se se Se	

description

These Schottky TTL eight-bit universal registers feature multiplexed inputs/outputs to achieve full eight-bit data handling in a single 20-pin package. Two function-select inputs and two output-control inputs can be used to choose the modes of operation listed in the function table.

Synchronous parallel loading is accomplished by taking both function-select lines, S0 and S1, high. This places the three-state outputs in a high-impedance state, which permits data that is applied on the input/output lines to be clocked into the register. Reading out of the register can be accomplished while the outputs are enabled in any mode. A direct overriding input is provided to clear the register whether the outputs are enabled or off.

	INPUTS							INPUTS/OUTPUTS								OUTPUTS		
MODE	CLR	FUNC	TION ECT		TROL	CLK	SEF	NAL	A/QA	8/Q8	c/QC	D/QD	E/QE	F/QF	G/QG	н/Q _Н	۵ ₄ ,	ан
		S 1	\$0	G11	Ğ21		SL	SR										
	L	×	L	L	L	x	X	x	L	L	L	L	L	L	L	L	L	L
Ciear	L	L	×	L	L	x	×	x	ίL.	L	LL	L	L	L	L	L	L	L
	L	н	н	x I	x	×	X	×	×	×	×	×	×	×	x	×	L	L
t	н	L	L	L	Ľ	x	X	х	OA0	OBO	aco	000	QEO	QFO	QGO	QH0	QA0	а _{нс}
Hold	н	×	х	L.	L	L	×	x	QA0	0 ₈₀	a _{co}	0 _{D0}	QEO	∩¢0	D _{G0}	QHO	Q _{A0}	QHC
	н	+	н	L	L	÷	X	н	н	QAn	QBu	QCn	QDn	α _{En}	QFn	QGu	н	a _{Gr}
Shift Right	н	ι ι	н	L	L	•	X	L	L	QAn	QBn	üÇn	QDn.	QEn	OFn	QGn_	L	۵ _{Gr}
	н	н	L	L	L	•	н	X	QBn	a _{Cn}	۵pn	Q _{En}	QEn	QGn	Q _{Hn}	н	QBn	H
Shift Left	н	н	L	L .	Ł	•	L	×	QBn	a _{Cn}	Q _{Dn}	QEn	QFn	∆ _{Gn}	α _{Hn}	L	a _{Bn}	L
Load	н	<u>+ H</u>	н	X	х	T T	X	х	a	D	c	d	e	f	9	h	a	'n

FUNCTION TABLE

 a_{+++} h = the level of the steady state input at inputs A through H, respectively. These data are loaded into the flip-flops while the flip flop outputs are isolated from the input/output terminals.

PRODUCTION DATA documents contain information current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warrenty. Production processing does not necessarily include testing of all parameters.



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logic symbol[†]



 † This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for DW, J, N, and W packages.



logic diagram (positive logic)

Pin numbers shown are for DW, J, N, and W packages.



SN54LS299, SN74LS299 8-BIT UNIVERSAL SHIFT/STORAGE REGISTERS

schematics of inputs and outputs



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, VCC (see Note 1)	· · · · · · · · · · · · · · · · · · ·
Input voltage	· · <i>, ·</i> · · · · · · · · · · · · · · · · · ·
Operating free-air temperature range: SN54LS299	
Storage temperature	

NOTE 1: Voltage values are with respect to network ground terminal.

recommended operating conditions

		s	N54LS2	99	SN74LS299			
		MIN	NOM	MAX	MIN	NOM	MAX	
Supply voltage, VCC		4.5	5	5.5	4.75	5	5,25	V
High-level output current, IOH	Q _A thru Q _H			1			-2.6	mA
High level batbat carrent, 10H	Q _A ' or Q _H '			-0.4			-0.4	
	Q _A thru Q _H			12		_	24	mA
Low-level output current, IOL	Q _A , or Q _H ,			4			8	
Clock frequency, fclock		0		20	0		20	MHz
Width of clock pulse, tw(clock)	Clock high	30			30			
	Clack law	18			10			ns
Width of clear pulse, tw(clear)	Clear low	25			20	_		ns
	Select	35*			351			
	High-level data [†]	201			201]
Setup time, t _{su}	Low-level data [†]	201			201			ns .
	Clear inactive-state	241			201			
	Select	101			101			
Hold time, t _h	Data [†]	31		;	01			ns
Operating free-air temperature, TA	· · · · · ·	-55		125	0		70	C

 † Data includes the two serial inputs and the eight input/output data lines.

SN54LS299, SN74LS299 **8-BIT UNIVERSAL SHIFT/STORAGE REGISTERS**

	PARAMETER		TEST COM	DITIONS T	SI SI	N54LS2	99	SI	174L52	99	UNIT
		· · · · · · · · · · · · · · · · · · ·	TEST CONDITIONS [†]			түр∔	MAX	MIN	ΤΥΡ	MAX	
⊻ін	High-level input voltage				2			2			V
VIL	Low-level input voltage						0.7	<u> </u>		0.8	V
VIK	/IK Input clamp voltage		VCC = MIN,	1 ₁ = -18 mA			-1.5	1		-1.5	V
Valu	High-level output voltage	QA thru QH		V _{IH} = 2 V,	2.4	3.2		2.4	3.1		
∨он	High-rever output vortage	Q _A ' or Q _H '	V _{IL} ≂ V _{IL} max,	I _{DH} = MAX	2.5	3.4		2.7 3.4			V
		Q _A thru Q _H	Vcc = MIN,	10L - 12 mA		0.25	0.4		0.25	0.4	
Ver	Low-level output voltage		V _{IH} = 2 V,	1 _{0L} = 24 mA					0.35	0.5	v
VOL	LOW-level Output voltage	QA' or QH'	VIL = Vil max	10L = 4 mA		0.25	0.4		0.25	0.4	
		CALOR CH.		1 _{0L} = 8 mA					0.35	0.5	
1	Off-state output current,	Q _A thru Q _H	V _{CC} = MAX,	$V_{III} = 2 V,$			40			10	
lоzн	high-level voltage applied		Vo = 2.7 V				40		40	μA	
1071	Off-state output current,	QA thru QH VCC = MAX,	V _{CC} = MAX,	V _{IH} = 2 V,	T		-400			-400	
10ZL	low-level voltage applied	α _A uni α _H	V _O = 0.4 V		-40		-400			-400	μA
	Input current at maximum	SO, S1		Vi = 7 V			200			200	
4		A thru H	V _{CC} = MAX	V ₁ = 5.5 V			100			100	μA
	input voltage	Any other		V1 = 7 V			100			100	
1	blick local is not according	A thru H, S0, S1					40			40	
ΠH	High-level input current	Any other	V _{CC} = MAX,	V ₁ = 2.7 V			20			20	μA
		S0, S1					-0.8			-0.8	
ΙιL	Low-level input current	Any other	V _{CC} = MAX.	VI ≈ 0.4 V			-0.4			-0.4	mΑ
,	<u></u>	Q _A thru Q _H			-30		-130	-30		-130	
los	Short-circuit output current§	QA' or QH'	V _{CC} = MAX		-20		-100	-20		-100	mΑ
cc	Supply current		V _{CC} = MAX			33	53		33	53	mΑ

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

¹For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions. \ddagger Ail typical values are at V_{CC} = 5 V, T_A = 25°C.

 ${
m \$Not}$ more than one output should be shorted at a time and duration of the short-circuit should not exceed one second.

switching characteristics, VCC = 5 V, TA = 25° C

PARAMETER	FROM (INPUT)	то (ОUТРUТ)	TEST CONDITIONS	MIN	түр	МАХ		
fmax			See Note 2	20	35		MHz	
tpLH	CLK	QA' or QH'	$R_1 = 2 k\Omega$, $C_1 = 15 pF$	T	22	33		
[†] PHL						26	39	ns.
tPHL	CLR	QA' or QH'	7		27	40	ns	
(PLH		Q _A thru Q _H		1	17	25		
^t PHL	CLK	OA WILL OH	RL=065Ω. CL=45pf	Cu = 45 nE	26	39	ns	
^t PHL	CLR	QA thru QH		<u> </u>	26	40	ins	
tPZH	- <u>G</u> 1, <u>G</u> 2	Q _A thru Q _H	-		13	21		
tPZL					19	30	ns	
^t PHZ	<u>Ğ1, Ğ2</u>	Q _A thru Q _H	R _L - 665 Ω, C _L = 5 pF	ľ	10	20		
^t PLZ					10	15	ns 🛛	

 $f_{max} = maximum clock frequency$ $tp_LH = probagation delay time, low to-high level output$ $tp_LH = probagation delay time, high-to-low-level output$ $tp_ZH output enable time to high level$ $tp_ZL = output enable time to low level$ $tp_HZ = output disable time from high level$ $tp_ z = output disable time from high level$ $tp_ z = output disable time from low (evel$

 t_{PLZ} - output disable time from low level NOTE 2: For testing f_{Max} , all outputs are loaded simultaneously, each with CL and RL as specified for the propagation times. Load circuits and voltage waveforms are shown in Section 1.

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, VCC (see Note 1)
Input voltage
Off-state output voltage 5.5 V
Operating free-air temperature range: SN54S299 (See Note 1)55°C to 125°C
SN74S299
Storage temperature range

NOTE 1: Voltage values are with respect to network ground terminal.

recommended operating conditions

		5	SN54S29	9	;	SN74529	9	
		MIN	NOM	MAX	MIN	NOM	MAX	
Supply voltage, V _{CC}		4.5	5	5.5	4.75	5	5.25	V
	Q _A thru Q _H	1		-2			-6.5	mA
High-level output current, IOH	Q _A ' or Q _H '			-0.5			-0.5	
	Q _A thru Q _H	1		20			20	mA
Low-level output current, IOL	QA' or QH'			6			6	
Clock frequency, fctock	····· •	0		50	0		50	MH
Vidth of clock pulse, tw(clock)	Clock high	10			10			ns
	Clock low	10			10			115
Width of clear pulse, tw(clear)	Clear low	10			10			n 5
	Select	151			15†			
	High-level data [†]	71			7†			
Setup time, t _{su}	Low-level data [‡]	51			51			ns
	Clear inactive-state	101		·	10†			1
	Select	51			5 ↑			
Hold time, t _h	Data ‡	51			51			ns
Operating free-air temperature, TA		-55		125	0		70	С

 $^{\pm}$ Data includes the two serial inputs and the eight input/output data lines.



SN54S299, SN74S299 **8-BIT UNIVERSAL SHIFT/STORAGE REGISTERS**

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	PARAMETER		TEST CON	MIN	TYP‡	MAX	UNIT	
ViH	High-level input voltage				2			V
Vit	Low-level input voltage	· · ·					0.8	V
Vik	Input clamp voltage		Vcc - MIN,	lı – –18 mA			-1.2	V
Vau	High-level output voltage	QA thru QH	V _{CC} = MIN,	V _{IH} = 2 V,	2.4	3,2		
∨он	rightever burbur vortage	QA' or QH'	V _{IL} = 0.8 V.	IOH = MAX	2.7	3.4		V V
νοι	l nw-level output voltage	· · · · · · · · · · · · · · · · · · ·	Vcc = MIN,	VIH = 2 V,				V
• OL	enwicker darpar vortrige		V _{IL} = 0.8 V,	IOL = MAX			0.5	V V
lozu	Off-state output current,	Q _A thru Q _H	VCC - MAX,	V _{IH} = 2 V,				
lozн	high-level voltage applied		Vo = 2.4 V				100	μA
IOZL	Off-state output current,	Out three Out	V _{CC} = MAX.	V _{IH} = 2 V,	T			ſ .
102L	low-level voltage applied	Ω _A thru Δ _H	V _O = 0.5 V				250	μA
(j	Input current at maximum input voltage		V _{CC} = MAX,	Vj ~ 5.5 V			1	mΑ
цн	High-level input current	A thru H, S0, S1		V - 27.V			100	
H		Any other	VCC = MAX,	v = 2.7 V			50	1 µA
		CLK or CLR					-2	mA
4E	Low-level input current	S0, S1	VCC MAX,	Vi = 0.5 V			-500	μA
		Any other					-250	μА
tos	Short-circuit output current §	Q _A thru Q _H	Vac - MAY		-40		-100	
-05	Short Excer Carpar Contents	QA or QH	V _{CC} = MAX		-20		-100	mA
'cc'	Supply current		V _{CC} = MAX			140	225	mA

[†]For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

[‡]All typical values are at V_{CC} = 5 V, T_A = 25 C.

 $\frac{1}{2}$ Not more than one output should be shorted at a time and duration of the short circuit should not exceed one second.

switching characteristics, VCC = 5 V, TA = 25° C

PARAMETER¶	FROM (INPUT)	TO (OUTPŲT)	TEST CONDITIONS	MIN	түр	MAX	דואט
f _{max}			See Note 2	50	70		MHz
^t PLH	CLK		$R_{1} = 1 k\Omega, C_{1} = 15 pF$		12	20	
1PHL					13	20	ns
^t PHL	CLR	QA' or QH'			14	21	ns
TPLH	CLK	Q _A thru Q _H			15	21	
^t PHL		CA IND CH			15	21	ns
tPHL		Q _A thru Q _H	$R_{L} = 280 \ \Omega, C_{L} = 45 \ pF$		16	24	ns
ФZH	<u>G</u> 1, <u>G</u> 2	Q _A thru Q _H			10	18	
^t PZL]				12	18	ns
^t PHZ	Ğ1, Ğ2	Q _A thru Q _H	$R_{L} = 280 \Omega, C_{L} = 5 pF$		7	12	
^t PLZ					7	12	ns

fmax = maximum clock frequency

 t_{PLH} = Propagation delay time, low-to-high-level output

 t_{HHL} = Propagation delay time, high-to-low-level output

 t_{PZH} = output enable time to high level

 $tp_{\overline{Z}I}$ = output enable time to low level

 t_{PHZ} = output disable time from high level

 $r_{PLZ}^{(1)}$ = output disable time from low level NOTE 2: For testing f_{max}, all outputs are loaded simultaneously, each with C_L and R_L as specified for the propagation times Load circuits and voltage waveforms are shown in Section 1.



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